



13th IEEE European Test Symposium

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<http://www.ieee-ets.org>



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Call for Papers

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, practical applications, hot topics, and new trends in the area of electronic-based circuit and system testing. In 2008, ETS will take place in the nice town of Verbania, Piedmont, Lago Maggiore lakeside. ETS'08 is being organized by the Politecnico di Torino, and is sponsored by the Test Technology Technical Council (TTTC) of the IEEE Computer Society.

You are invited to participate and submit your contributions to ETS'08. The areas of interest of ETS'08 include (but are not limited to) the following topics:

- Automatic Test Generation
- Fault Modeling and Simulation
- Current-Based Test
- Power Issues in Test
- Thermal Test
- Delay and Performance Test
- High-Speed IO/Interconnect Test
- Signal Integrity Test
- Nanometer Technologies Test
- ATE Hardware and Software
- Standards in Testing
- Test(ability) Synthesis
- Built-In Self Test (BIST)
- Design for Test(ability) (DfT)
- Test Data Compression
- On-Line Test
- Self-Repair Methodologies
- Test of Reconfigurable Systems
- Analog, Mixed-Signal, RF Test
- Memory Test and Repair
- Microprocessor Test
- MEMS and Nanotechnology Test
- Failure Analysis
- Diagnosis and Debug
- Design Verification and Validation
- Test Quality and Reliability
- Yield Analysis and Enhancement
- Defect and Fault Tolerance
- Board and System Test
- (Embedded) System Test
- High-Level DfT and TPG
- System-in-Package (SiP) Test
- System-on-Chip (SoC) Test

Publications – ETS'08 will produce a *Formal Proceedings*, published by the IEEE Computer Society, and a *Web-based Electronic Informal Digest* of the selected papers. The best contributions will be selected for submission to regular issues of the "Journal of Electronic Testing: Theory and Applications" (JETTA), published by Springer. ETS'08 will present a Best Paper Award at ETS'09.

Submissions – ETS'08 seeks original, unpublished contributions of the following types:

- scientific papers presenting novel and complete research work
- workshop-type papers, including 'emerging ideas' and 'case studies'
- 'Vendor Session' presentations focusing on new features of test-related products
- proposals for panels, embedded tutorials, and other special sessions.

Detailed submission instructions, including selection criteria and publication policies, for the various types of contributions are posted on the ETS web page.

TTTC Test Technology Educational Program (TTEP) tutorials on emerging test technology topics will be offered during ETS'08. Tutorial proposals should be submitted according to TTEP 2008 submission deadlines (<http://computer.org/tab/ttcc/teg/ttep>).

As a new initiative for ETS'08, the organizing committee would like to encourage the organization of fringe workshops and will provide extensive support for the organization of such events. Full details can be found on the ETS web page.

Key Dates:

- Submission deadline : **December 7, 2007**
- Notification of acceptance : **February 17, 2008**
- Camera-ready manuscript : **March 16, 2008**

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